

Form PTO 100
(Modified)U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

ATTY DOCKET NO.

249406US2SRD

SERIAL NO.

10/786,290

LIST OF REFERENCES CITED BY APPLICANT

APPLICANT

Akira FUJIMOTO, et al.

FILING DATE

February 26, 2004

GROUP

1756

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
/AA/	AO	2002-122702	04/26/2002	Japan		X
/AA/	AP	2001-74919	03/23/2001	Japan		X
	AQ					
	AR					
	AS					
	AT					
	AU					
	AV					

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

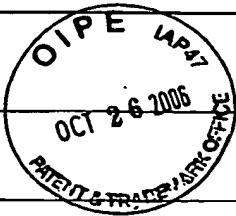
	AW	
	AX	
	AY	
	AZ	

☐ Additional References sheet(s) attached

Examiner /Anita Alanko/

Date Considered 04/01/2007

*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



	Docket No.: 249406US2SRD	Serial No.: 10/786,290
LIST OF RELATED CASES CITED BY APPLICANT UNDER 37 CFR 1.56	Inventor: Akira FUJIMOTO, et al.	
	Filing Date: February 26, 2004	Group: 1756

LIST OF RELATED CASES

Examiner Initial	Docket No.	Serial or Patent Number	Filing or Issue Date	Patent App. Publication No.	Inventor or Applicant	Client's Reference No.
/AA/	249406US2SRD	10/786,290	02/26/04		FUJIMOTO, et al.	13G036033-USA-A T7KT-0331042
/AA/	294294US2SRD DIV	11/493,807	07/27/06		HIEDA, et al.	13G032584-USA-A T7KO-01S1116-D2

Examiner /Anita Alanko/

Date Considered 04/01/2007

*Present Application; listed for information
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Form PTO 1449
(Modified)U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY DOCKET NO.
249406US2SRDSERIAL NO.
New Application

LIST OF REFERENCES CITED BY APPLICANT

APPLICANT

Akira FUJIMOTO, et al.

FILING DATE

Herewith

GROUP

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
/AA/	AA	5,779,924	07/14/98	Michael R. KRAMES, et al.			
/AA/	AB	4,554,727	11/26/85	Harry W. DECKMAN, et al.			
	AC						
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	AM						
	AN						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
/AA/	AO	8-167738	06/25/96	JAPAN		X
/AA/	AP	2000-299494	10/24/2000	JAPAN		X
/AA/	AQ	4-354382	12/08/92	JAPAN		X
	AR					
	AS					
	AT					
	AU					
	AV					

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

/AA/	AW	Y. KANAMORI, et al., "100 NM PERIOD SILICON ANTIREFLECTION STRUCTURES FABRICATED USING A POROUS ALUMINA MEMBRANE MASK", Applied Physics Letters, Vol. 78, No. 2, January 8, 2001, pgs. 142-143				
/AA/	AX	Yoshiaki KANAMORI, et al., "BROADBAND ANTIREFLECTION GRATINGS FOR GLASS SUBSTRATES FABRICATED BY FAST ATOM BEAM ETCHING", Jpn. J. Appl. Phys., Vol. 39, July 15, 2000, pgs. L735-L737				
/AA/	AY	Y. INOMATA, et al., "SURFACE TEXTURING OF LARGE AREA MULTICRYSTALLINE SILICON SOLAR CELLS USING REACTIVE ION ETCHING METHOD", Solar Energy Materials and Solar Cells, Vol. 48, 1997, pgs. 237-242				
	AZ				<input type="checkbox"/> Additional References sheet(s) attached	

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Date Considered 04/01/2007

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